

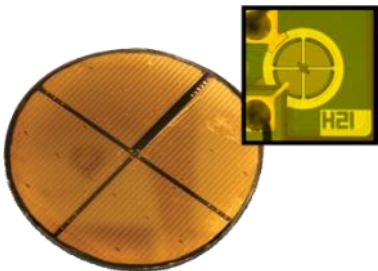
The logo for AEHR Test Systems features the company name in a bold, black, sans-serif font. To the right of the text is a graphic consisting of five horizontal orange bars of equal length.

AEHR **TEST SYSTEMS**

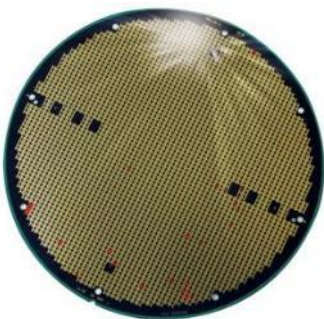
**Setting the Test Standard for
Tomorrow**

Nasdaq: AEHR

Solutions from Wafers to Package Parts



Wafer



Panel



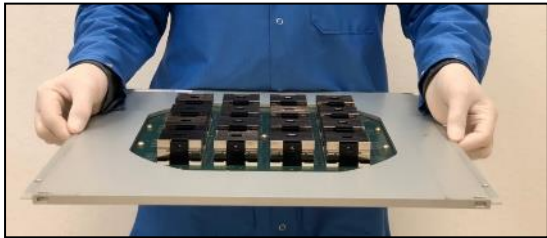
Die/Module



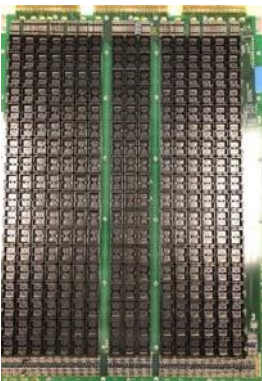
Package Parts



WaferPak



DiePak



BIB

Aehr Product Portfolio of Test & Burn-in Systems

Wafer/Die Level



FOX-*P* WaferPak
Contactor & DiePak Carrier



Engineering & NPI Dual Wafer
Test & Burn-In System



Single Wafer
Test & Burn-In System



Multi Wafer & Singulated Die
Test & Burn-In System

Package Part



ABTS Burn-in
Board



ABTS-L
72 Slot Test & Burn-In
System



ABTS-P
36 Slot High Power Test &
Burn-In System



MAX5
64 Slot High Power & Voltage
Test & Burn-In System

MAX5 Burn-in Test System

Serving the High Voltage Power Devices, Automotive, and IoT markets with:

- 48 slots (each is its own pattern zone)
- Up to 9 power supplies per BIB
- High Voltage Options
- 128 bi-directional test channels
- Advanced DUT Monitoring
- DUT Current Measurements
- Individual Thermal Control
- Simple and Complex Test Plans
- GUI Programming interface
- Optional MAX3-compatible config

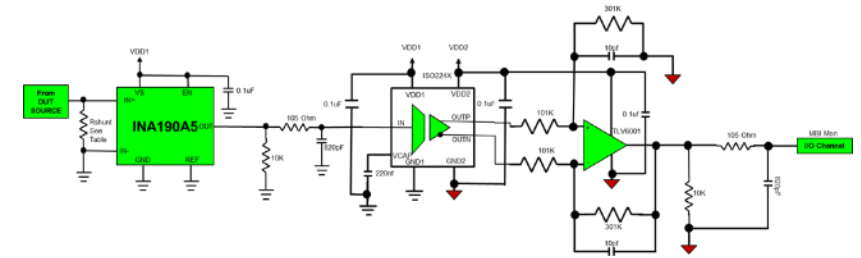


High Voltage Done Safely and Effortlessly

- Up to 1,000V, 1,600V, and 1,900V options
- Designed for safety
 - Operator safety protections
 - Safety interlocks and emergency off
 - Clearances and creepages to prevent arcing
 - Isolated HV power sources and returns
 - Over voltage, over current protection
 - Short circuit protection
 - Output arcing protection
 - Software monitoring for OV, OC, OT
- Compliance with safety standards
 - IEC 62368-1 (aka UL-62368-1)
 - SEMI S22, IEEE 510-1983
- HV BIBs are supplied by Aehr Test Systems

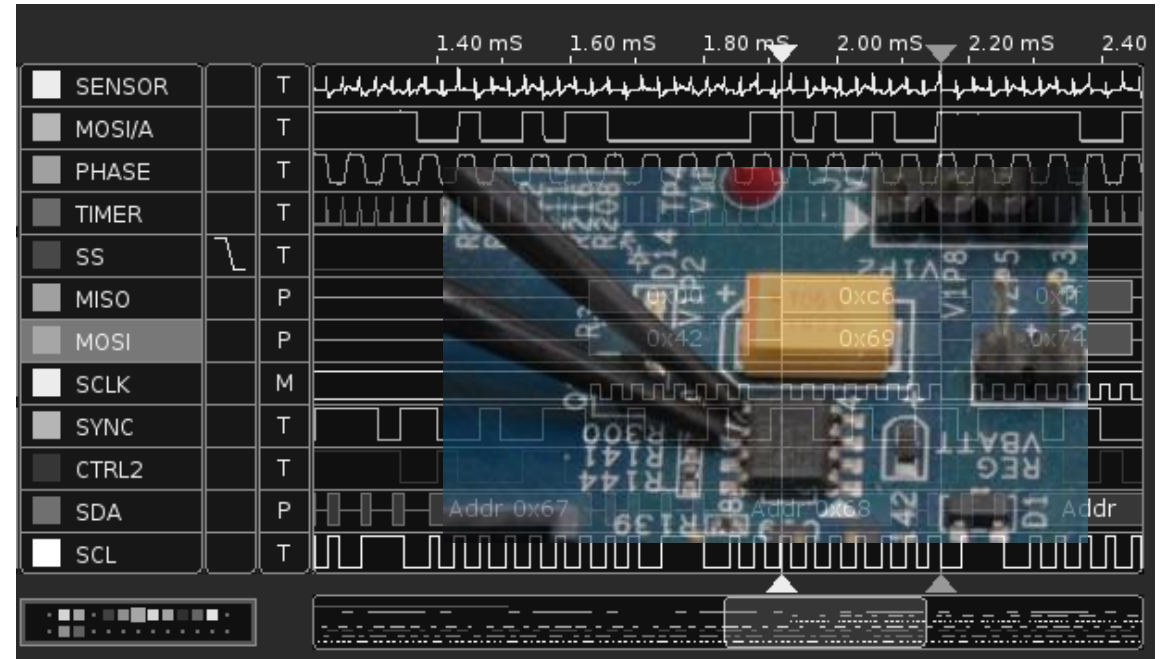
Fine Tune Your Burn-in Strategy

- Measure voltage or current PER DUT
 - Voltage measurement: 1mV to 2,000V
 - Current measurement: 1uA to 100A
- Optimize stress voltage & BI time
- Automatically datalog measurements
- Identify failures when they happen
- Programmable shutdown on fail



Know How Your Devices are Performing Under Stress

- Real-time monitoring & testing during burn-in
 - Expected data compare
 - Sign of life detection
 - Voltage measurement
 - Current measurement
 - Temperature measurement
- Fault trigger and logging
- Shutdown trigger and logging



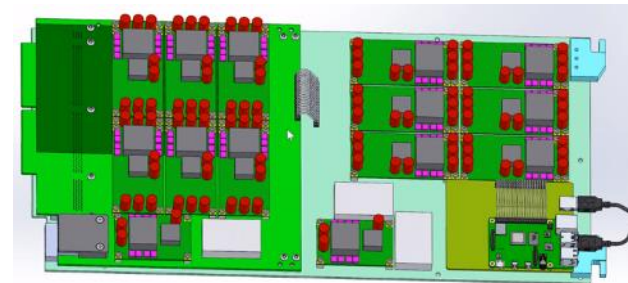
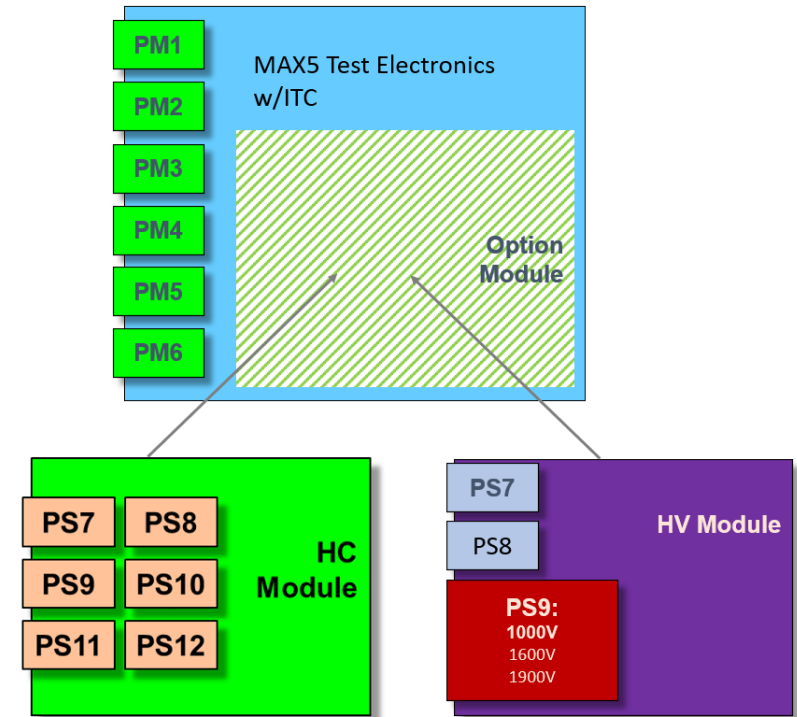
MAX5 Chamber



- Up to 64 Slots (48 slots for HV option)
- 1.8" (45.7mm) or 2.4" (61mm) slot pitch
- Airflow: up to 6,000 cfm
- Burn-in Temperature up to 150°C
- Power Dissipation: Up to 36kW @ 150°C
- Safety features:
 - Electronic safety interlocks
 - High voltage shielding and barriers
 - EPO switches
- Optional compatibility with MAX3 BIBs

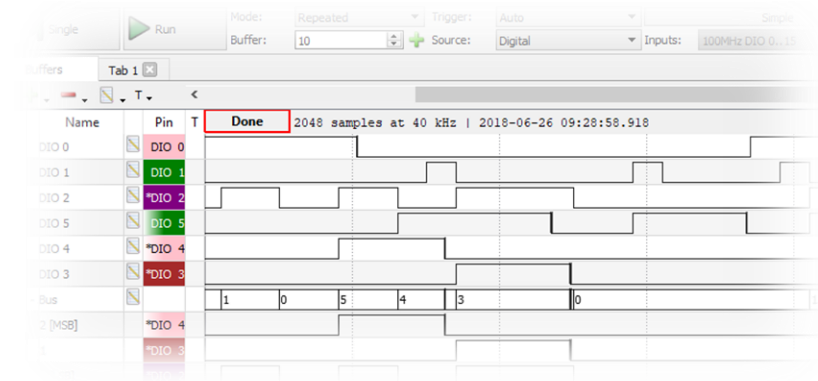
MAX5 DUT Power Supplies per Slot

- Standard up to six PS Modules per slot:
 - Available interchangeable PS modules:
 - 0.7 to 7.5V / 25A (200W max)
 - 1 to 20V / 15A (200W max)
 - 1 to 60V / 1A (60W max)
 - Per PS or per DUT current monitoring
 - All PS are fully programmable
- Optional High Voltage Add-on per slot
 - Up to 1000V, 1600V, 1900V (200mA max)
 - Plus two floating +/- 32V (5A) PS
- Optional High Current Add-on per slot (future)
 - Additional six 4V @ 50A modules
 - Can be ganged in pairs for three 4V @ 100A



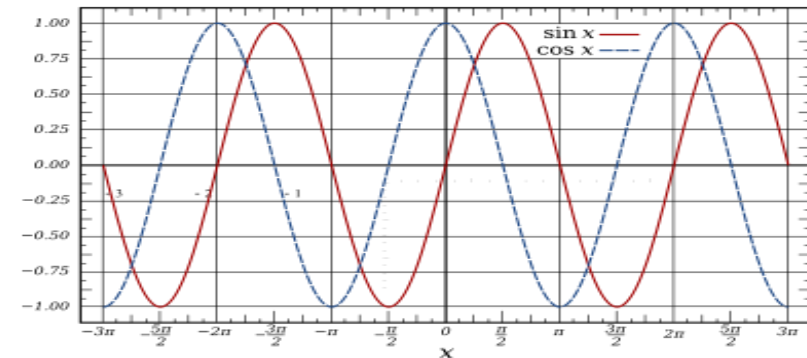
MAX5 Test Electronics per Slot

- Each BIB is its own test zone
- Up to 128 bi-directional channels
 - Vector pattern/compare data channels
 - Analog measurement channels
- Pin driver electronics
 - Programmable VIH to 8V
 - Two programmable VIH levels
 - Two programmable Vth levels
 - High speed pin drivers
 - 64 timing sets, assign per pin
- Voltage & current measure
 - Per DUT measurement
 - Shutdown on over limit
- Software
 - GUI operating software, test plan programming and pattern development
- Pattern generator module
 - 128 channels, 32M vectors deep
 - NRZ, RZ, RO, Tristate
 - Up to 20MHz data rate (50ns)
 - Repeat and loop commands

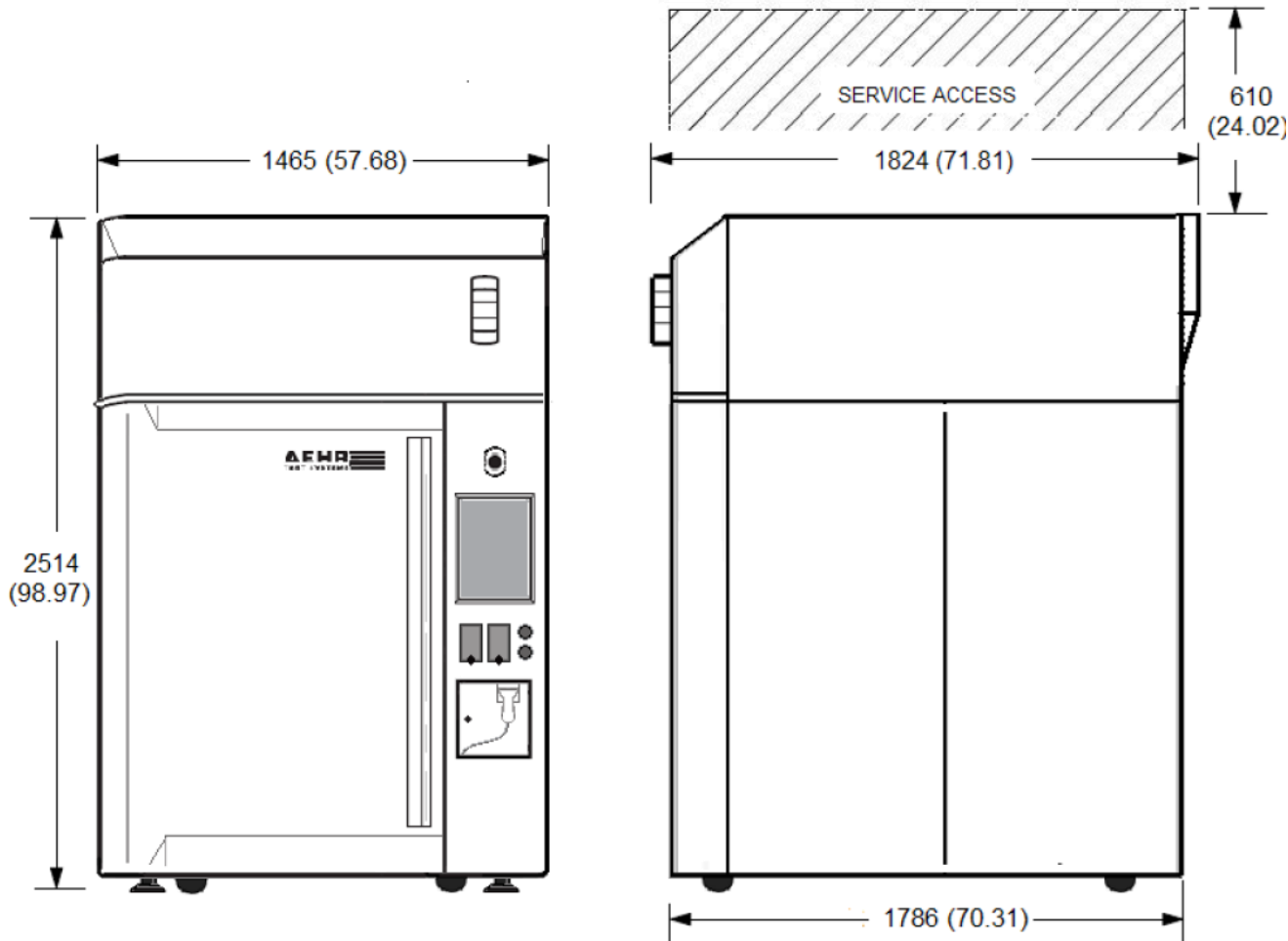


MAX5 Communications, ITC, and Analog Options

- Individual DUT Temp Control (future)
 - T_{CASE} or calculated $T_{JUNCTION}$ temp control
 - On-DUT thermal diode readout
 - Shutdown on temperature limits
 - On-socket heater, sensor & heatsink
 - Up to 150°C
- Communications
 - I2C engine for DUT comms
 - Bit-rate programmable
 - Up to 20Mbps
 - Fast program download
- Analog frequency generator (future)
 - Programmable sine & triangular wave up to 20MHz
 - Programmable amplitude & freq
 - Up to 8 distinct signals
- HF Clocks
 - Up to 200MHz, LVDS

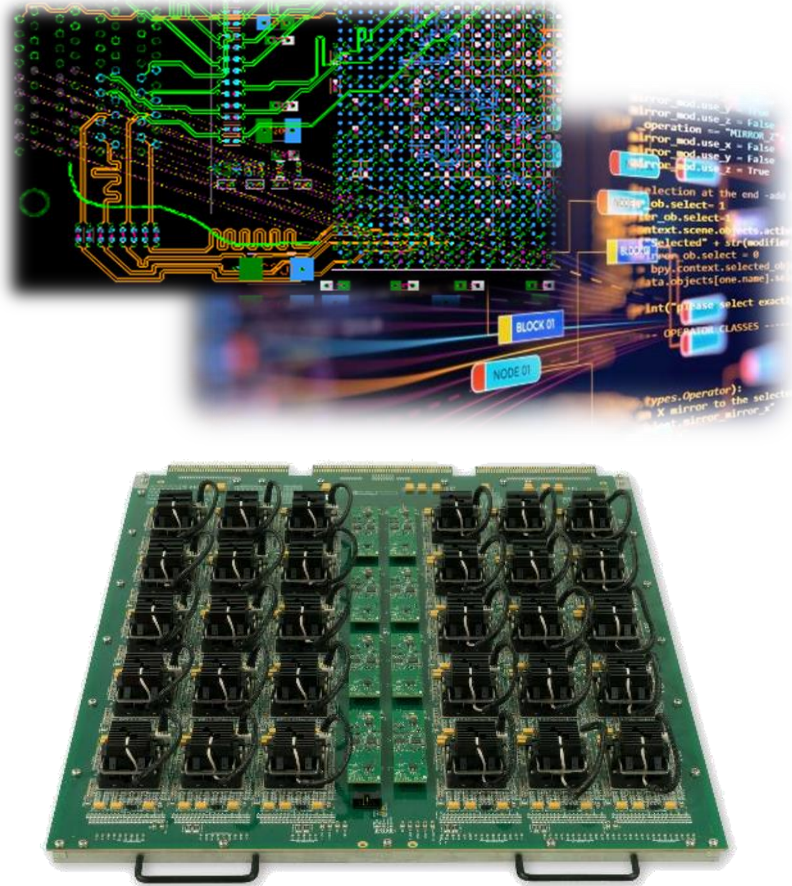


MAX5 Facilities Requirements (preliminary)



- Dimensions:
 - 58"W x 70"D x 99"H
 - approx 3200 lbs.
- Electrical
 - 208V, 3-phase (5 wires), 150A
- Water
 - 12-20 gpm, 40-90 psi
 - 15-21°C
 - 1 supply, 1 return
- A detailed Installation & Maintenance Guide will be provided with the system

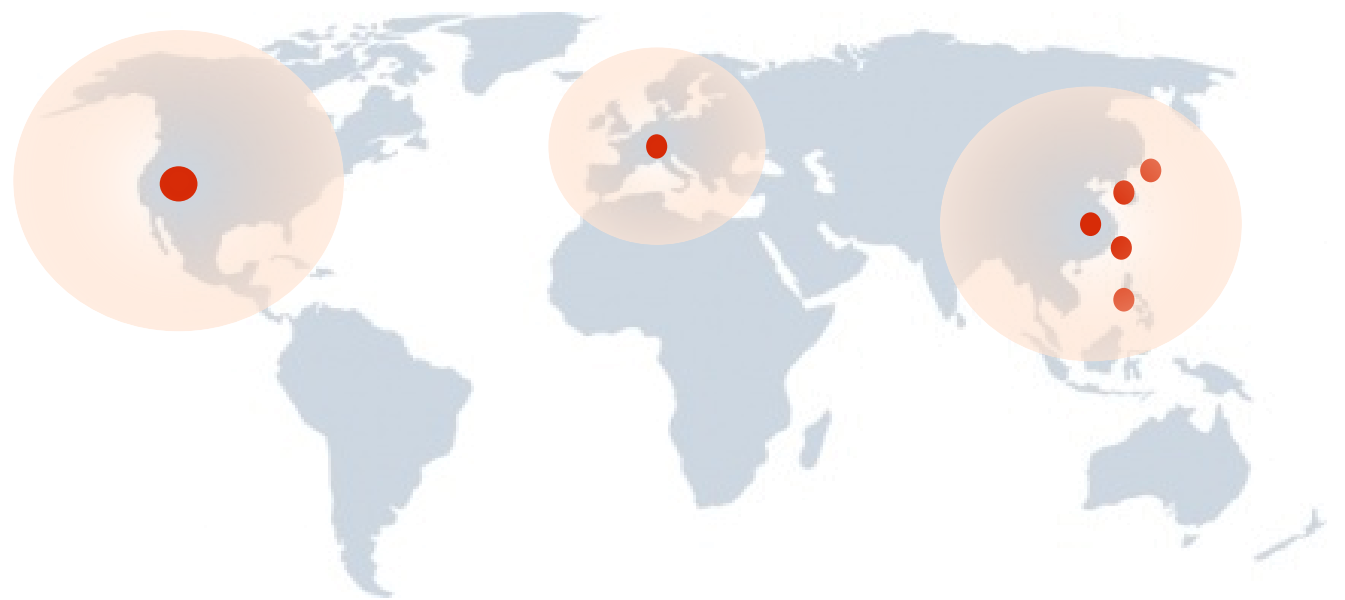
Applications Development (BIB and Programming)



- Application Development:
 1. Specs review (electrical & mech.)
 2. Schematic and circuit design
 3. PCB layout and schematic capture
 4. SI simulation if needed
 5. Fabrication, assembly & BIB test
 6. Applications programming
 7. Product bring-up
- MAX5 BIB Dimensions:
 - 11.45"W x 24"L x 0.125"
 - Up to 24 layers
 - Up to 128 channels
 - HV up to 1,900V

Installed Base and Support

- Aehr Test Systems Installed Base
 - Over 2500 systems worldwide over 40 years
 - Installations in Asia, Europe, and North America
 - Customers include Tier 1 IDMs and OSATs
- Worldwide Support
 - USA: 7 service & apps engineers
 - Philippines: 16 service engineers
 - Taiwan: 5 service engineers
 - China: 3 services engineers
 - Korea: 1 service engineer
 - Japan: 1 service engineer
- Contact: www.aehr.com



The logo for AEHR Test Systems is centered in the upper half of the image. It features the letters 'AEHR' in a large, bold, black sans-serif font. Below 'AEHR' is the text 'TEST SYSTEMS' in a smaller, bold, black sans-serif font. To the right of the text is a graphic element consisting of five horizontal orange bars of equal length.

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